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(54) **METHODS OF DESIGNING A LAYOUT OF A SEMICONDUCTOR DEVICE INCLUDING FIELD EFFECT TRANSISTOR AND METHODS OF MANUFACTURING A SEMICONDUCTOR DEVICE USING THE SAME**

(71) Applicants: **TAEJOONG SONG, SEONGNAM-SI (KR); SANCHOON BAEK, SEOUL (KR); SUNGWE CHO, HWASEONG-SI (KR); JUNG-HO DO, YONGIN-SI (KR); GIYOUNG YANG, SEOUL (KR); JINYOUNG LIM, SEOUL (KR)**

(72) Inventors: **TAEJOONG SONG, SEONGNAM-SI (KR); SANCHOON BAEK, SEOUL (KR); SUNGWE CHO, HWASEONG-SI (KR); JUNG-HO DO, YONGIN-SI (KR); GIYOUNG YANG, SEOUL (KR); JINYOUNG LIM, SEOUL (KR)**

(73) Assignee: **SAMSUNG ELECTRONICS CO., LTD., SUWON-SI (KR)**

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#### ABSTRACT

A method of designing a semiconductor device includes preparing a standard cell layout including a layout out a preliminary pin pattern in at least one interconnection layout, performing a routing step to connect the preliminary pin pattern to a high-level interconnection layout, and generating a pin pattern in the interconnection layout, based on hitting information obtained at the completion of the routing step. The pin pattern is smaller than the preliminary pin pattern.

